

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Shunpei Yamazaki et al.                      Art Unit : 2812  
Serial No. : 10/765,952                                      Examiner : Richard A. Booth  
Filed : January 29, 2004                                      Conf. No. : 2326  
Title : SEMICONDUCTOR DEVICE AND METHOD OF MANUFACTURING THE  
SAME

MAIL STOP RCE  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Applicants request consideration of the references listed on the attached PTO-1449 form. Under 37 C.F.R. § 1.98 (a)(2)(ii), only copies of foreign patent documents and/or non-patent literature are enclosed. Copies of any listed U.S. patents or U.S. patent application publications can be provided upon request.

Submitted herewith are English translations of the following foreign language references, or portions thereof:

Desig. ID	Source
AL	Japan 8-032081 – English Abstract: esp@cenet.com.
AM	Japan 62-248255 – English Abstract: esp@cenet.com.

This filing is being made with the filing of a Request for Continued Examination. No fee is required.

Respectfully submitted,

Date: August 22, 2007

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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. <b>07977-247002</b>	Application No. <b>10/765,952</b>
<b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary)		Applicant <b>Shunpei Yamazaki et al.</b>	
		Filing Date <b>January 29, 2004</b>	Group Art Unit <b>2812</b>
(37 CFR §1.98(b))			

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL	JP 8-032081	02/02/1996	Japan			AB	
	AM	JP 62-248255	10/29/1987	Japan			AB	
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AQ	
	AR	
	AS	
	AT	

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	